## 

WESTERN DIGITAL TECHNOLOGIES, INC., Petitioner

v.

OCEAN SEMICONDUCTOR LLC,
Patent Owner

\_\_\_\_

Case No. IPR2021-00929 Patent No. 7,080,330

PETITIONER'S UPDATED LIST OF EXHIBITS

## **LIST OF EXHIBITS**

Exhibit No.	Description
1001	U.S. Patent No. 7,080,330
1002	File History of U.S. Patent No. 7,080,330
1003	Declaration of Dr. Alexander Glew (with curriculum vitae)
1004	U.S. Patent No. 6,891,627 to Levy
1005	U.S. Patent Application Publication No. 2003/0160163 to Wong
1006	U.S. Patent Application Publication No. 2002/0072001 to Brown
1007	U.S. Patent No. 7,804,994 to Adel
1008	U.S. Prov. Patent App. No. 60/234,323 to Levy
1009	U.S. Prov. Patent App. No. 60/202,372 to Brown
1010	U.S. Prov. Patent App. No. 60/357,390 to Adel
1011	U.S. Prov. Patent App. No. 60/419,786 to Adel
1012	U.S. Prov. Patent App. No. 60/435,878 to Adel
1013	Wolf et al., Silicon Processing for the VLSI Era, Volume 1:
	Process Technology, Lattice Press, 2000 (excerpt)
1014	Van Zant, Microchip Fabrication: A Practical Guide to
	Semiconductor Processing, 3rd Ed., McGraw-Hill, 1997 (excerpt)
1015	Complaint (Dkt.No. 1) filed in Ocean Semiconductor LLC v.
	Western Digital Technologies, Inc., No. 6:20-cv-01216 (W.D.
	Tex.), with Exhibits A-G thereto
1016	Article titled "District Court Trial Dates Tend to Slip After PTAB
	Discretionary Denials" (July 24, 2020)
1017	Statistics from DocketNavigator showing active patent cases
	before Judge Albright of the U.S. District Court for the Western
	Digital of Texas (as of May13, 2021)
1018	Complaints(Dkt. No. 1) filed in Ocean Semiconductor LLC v.
	MediaTek Inc., No. 6:20-cv-01210 (W.D. Tex.); Ocean
	Semiconductor LLC v. NVIDIA Corp., No. 6:20-cv-01211 (W.D.
	Tex.); Ocean Semiconductor LLC v. NVIDIA Corp., No. 6:20-cv-
	01211 (W.D. Tex.); Ocean Semiconductor LLC v. NXP
	Semiconductors NV, No. 6:20-cv -01212 (W.D. Tex.); Ocean
	Semiconductor LLC v. Renesas Electronics Corp., No. 6:20-cv-
	01213 (W.D. Tex.); Ocean Semiconductor LLC v. Silicon

Exhibit No.	Description
	Laboratories Inc., No. 6:20-cv-01214 (W.D. Tex.); Ocean
	Semiconductor LLC v. ST Microelectronics Inc., No. 6:20-cv-
	01215 (W.D.Tex.)
1019	Murnane et al., Scatterometry for 0.24-0.70 um developed
	photoresist metrology, Proc. SPIE 2439, Integrated Circuit
	Metrology, Inspection, and Process Control IX, May 22, 1995
1020	Bishop et al. Grating line shape characterization
	usingscatterometry, Proc. SPIE 1545, International Conference on
	the Application and Theory of Periodic Structures, Oct. 1, 1991
1021	Pforret al., In-process image detection technique for determination
	of overlay and image quality for ASM-L wafer stepper, Proc.
	SPIE 1674, Optical/Laser Microlithography V, June 1, 1992
1022	1993 DARPA Final Report, Overlay and Grating Line Shape
	Metrology Using Optical Scatterometry (unclassified), unlimited
	release Nov. 20, 2001
1023	Mori et al., Multi-batch Preparation of Standard Samples from a
	Single Doped Solution for Cross-Checking in Surface Metal
	Analyses of Silicon Wafers, Analytics Sciences, Vol. 16, Sept.
	2000
1024	J. R. McNeil, et al., Scatterometry applied to microelectronic
	processing, Microlithography World 1(15), 1992
1025	U.S. Patent No. 5,701,013 to Hsai
1026	U.S. Patent No. 6,429,943 to Opsal
1027	Declaration of L. Kieran Kieckhefer in support of pro hac vice
	admission
1028	Transcript of Deposition of Kurt D. Humphrey, dated April 14,
	2022

## **CERTIFICATE OF SERVICE**

I hereby certify that the foregoing Petitioner Western Digital Technologies, Inc.'s Updated List of Exhibits was served on May 5, 2022, via electronic mail upon counsel of record for Patent Owner at the following email addresses:

Timothy Devlin
TD-PTAB@devlinlawfirm.com
Alex Chan
achan@devlinlawfirm.com
Joel Glazer
jglazer@devlinlawfirm.com
Henrik D. Parker
hparker@devlinlawfirm.com
dlflitparas@devlinlawfirm.com

SHEARMAN & STERLING LLP

/Patrick R. Colsher/
Patrick R. Colsher (Reg. No. 74,955)